

**Search Notes**

Application/Control No.

10/655,390

Examiner

Sun J. Lin

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	4	1/9/2006	JSL
716	5	1/9/2006	JSL
716	1	1/9/2006	JSL
703	18	1/9/2006	JSL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
716	4	1/9/2006	JSL
716	5	1/9/2006	JSL
716	1	1/9/2006	JSL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT;US- PGPUB;EPO;JPO;DERWENT;IBM_T DB]	1/9/2006	JSL
IEEE	1/9/2006	JSL